

**10/565123**

**IAP20 Rec'd PCT/PTO 19 JAN 2006**

Docket No.: 034337-0429

**PATENT**

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of : Customer Number: 20277  
Ion BENEÀ, et al. : Confirmation No.: Not yet assigned  
Application No.: Not yet assigned : Group Art Unit: Not yet assigned  
Filed: January 19, 2006 : Examiner: Not yet assigned

For: APPARATUS FOR MEASURING THE CRUSHING STRENGTH OF MICRON SUPERABRASIVES

**INFORMATION DISCLOSURE STATEMENT**

Honorable Commissioner for Patents and Trademarks  
Washington, D. C. 20231

Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached form PTO-1449. It is respectfully requested that the references be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed with the application and no certification or fee is required.

A copy of the foreign search report is attached for the Examiner's information. Please note this is a PCT application in the entry of the National Phase in the U.S. and copies of the references cited were transmitted by WIPO and are believed to be in the file of the above identified application and readily available to the Examiner. Therefore it is believed that Applicants have met all requirements regarding duty of disclosure under 37

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CFR 1.56. Acknowledgement and consideration of these documents are respectfully requested.

However, to ensure that these references are available to the Examiner, we are providing copies of these references herewith. Since the Search Report was from the U.S. search authority, copies of these references should have been supplied to the USPTO under the trilateral agreement and are believed to be in the file of the above identified application and readily available to the Examiner.

Respectfully submitted,

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**Please recognize our Customer No. 20277  
as our correspondence address.**

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SHEET 1 OF 1

| INFORMATION DISCLOSURE<br>CITATION IN AN<br>APPLICATION                 |          |   |                                | ATTY. DOCKET NO.<br><b>034337-0429</b>          | SERIAL NO.<br><b>Not yet assigned</b><br><b>10/565123</b> |   |
|---|----------|---|--------------------------------|---|---|---|
|   |          |   |                                | APPLICANT<br><b>Ion BENEÀ, et al.</b>           |   |   |
| (PTO-1449)  |          |   |                                | FILING DATE<br><b>January 19, 2006</b>          | GROUP<br><b>Not yet assigned</b>                          |   |
| <b>U.S. PATENT DOCUMENTS</b>  |          |   |                                |   |   |   |
| EXAMINER'S INITIALS   | CITE NO. | Document Number<br>Number-Kind Code <sub>2</sub> ( <i>if known</i> )  | Publication Date<br>MM-DD-YYYY | Name of Patentee or Applicant of Cited Document |   | Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear |
|   | US       | 3,713,592   | 01-30-1973                     | Beike et al.                                    |   |   |
|   | US       | 3,831,437   | 08-27-1974                     | Sheets et al.                                   |   |   |
|   | US       | 5,402,366   | 03-28-1995                     | Kihara et al.                                   |   |   |
|   | US       | 5,454,260   | 09-03-1995                     | Wang et al.                                     |   |   |
|   | US       |   |                                |   |   |   |
|   | US       |   |                                |   |   |   |
|   | US       |   |                                |   |   |   |
|   | US       |   |                                |   |   |   |
|   | US       |   |                                |   |   |   |
|   | US       |   |                                |   |   |   |
|   | US       |   |                                |   |   |   |
|   | US       |   |                                |   |   |   |
| <b>FOREIGN PATENT DOCUMENTS</b>   |          |   |                                |   |   |   |
| EXAMINER'S INITIALS   | CITE NO. | Foreign Patent Document<br>Country Codes-Number +-Kind Codes ( <i>if known</i> )  | Publication Date<br>MM-DD-YYYY | Name of Patentee or Applicant of Cited Document | Pages, Columns, Lines Where Relevant Figures Appear       | Translation<br>Yes      No  |
|   |          |   |                                |   |   |   |
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|   |          |   |                                |   |   |   |
|   |          |   |                                |   |   |   |
| <b>OTHER ART</b> (Including Author, Title, Date, Pertinent Pages, Etc.) |          |   |                                |   |   |   |
| EXAMINER'S INITIALS   | CITE NO. | Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published. |                                |   |   |   |
|   |          |   |                                |   |   |   |
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|   |          |   |                                |   |   |   |
| EXAMINER  |          |   | DATE CONSIDERED                |   |   |   |

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered.  
Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.